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November 2013

FDMC86116LZ N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 7.5 A, 103 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 103 m Ω at V_{GS} = 10 V, I_D = 3.3 A
- Max $r_{DS(on)}$ = 153 m Ω at V_{GS} = 4.5 V, I_D = 2.7 A
- HBM ESD protection level > 3 KV typical (Note 4)
- 100% UIL Tested
- RoHS Compliant

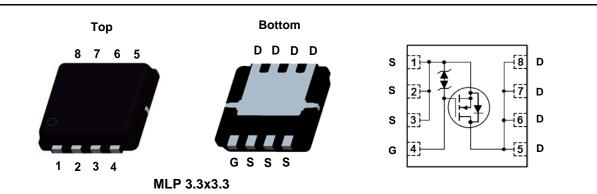


General Description

This N-Channel logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench[®] process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance. G-S zener has been added to enhance ESD voltage level.

Application

DC - DC Conversion



MOSFET Maximum Ratings $T_A = 25 \degree C$ unless otherwise noted

Symbol	Parameter Drain to Source Voltage			Ratings	Units V	
V _{DS}				100		
V _{GS}	Gate to Source Voltage			±20	V	
I _D	Drain Current -Continuous	T _C = 25 °C		7.5		
	-Continuous	T _A = 25 °C	(Note 1a)	3.3	А	
	-Pulsed			15		
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	12	mJ	
P _D	Power Dissipation	T _C = 25 °C		19	W	
	Power Dissipation	T _A = 25 °C	(Note 1a)	2.3	VV	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	6.5	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	C/VV

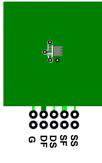
Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity	
FDMC86116Z	FDMC86116LZ	Power 33	13 "	12 mm	3000 units	

FDMC86116LZ N
I-Ch
Shielded G
annel Shielded Gate PowerTrencl
h [®] MOSFET

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_{D} = 250 \ \mu A, V_{GS} = 0 \ V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, referenced to 25 °C		73		mV/°C
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μA
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
On Chara	cteristics					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \ \mu A$	1.0	1.8	2.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, referenced to 25 °C		-6		mV/°C
U		V _{GS} = 10 V, I _D = 3.3 A		79	103	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 2.7 \text{ A}$	105 1		153	mΩ
20(01)		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3.3 \text{ A}, \text{ T}_{J} = 125 \text{ °C}$		136	178	-
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 3.3 A		11		S
Dynamic C _{iss}	Characteristics			232	310	pF
C _{oss}	Output Capacitance	$-V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$		45	60	pF
C _{rss}	Reverse Transfer Capacitance	f = 1 MHz		2.4	5	pF
R _g	Gate Resistance			0.7		Ω
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time			4.5	10	ns
t _r	Rise Time	V_{DD} = 50 V, I _D = 3.3 A, V _{GS} = 10 V, R _{GEN} = 6 Ω		1.3	10	ns
t _{d(off)}	Turn-Off Delay Time			10	20	ns
t _f	Fall Time			1.4	10	ns
Q _{g(TOT)}	Total Gate Charge	$V_{GS} = 0 V$ to 10 V		4	6	nC
Q _{g(TOT)}	Total Gate Charge	$ \begin{array}{c} V_{GS} = 0 \ V \ to \ 10 \ V \\ V_{GS} = 0 \ V \ to \ 4.5 \ V \\ I_D = 50 \ V, \\ I_D = 3.3 \ A \end{array} $		2	3	nC
Q _{gs}	Total Gate Charge			0.8		nC
Q _{gd}	Gate to Drain "Miller" Charge			0.7		nC
Drain-Sou	Irce Diode Characteristics					
		V _{GS} = 0 V, I _S = 3.3 A (Note 2)		0.85	1.3	.,
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 2 A$ (Note 2)		0.82	1.2	- V
		· · · · · · · · · · · · · · · · · · ·				1
t _{rr}	Reverse Recovery Time	– I _F = 3.3 A, di/dt = 100 A/μs		33	54	ns

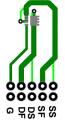
1. R_{0,JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



3. Starting T_J = 25 °C; N-ch: L = 1.0 mH, I_{AS} = 5.0 A, V_{DD} = 90 V, V_{GS} = 10 V.

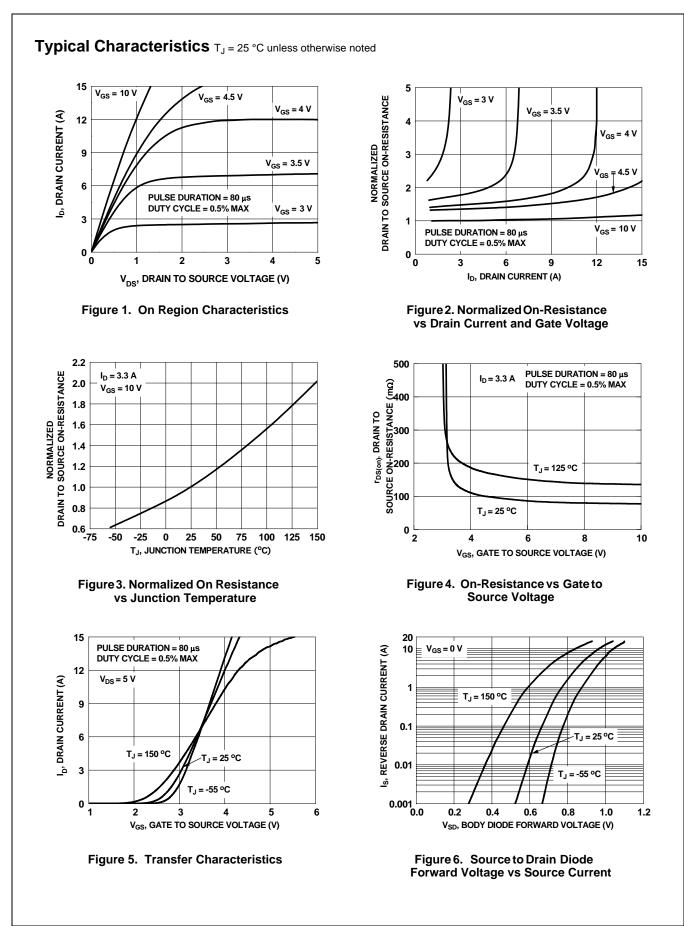
a. 53 °C/W when mounted on a 1 in² pad of 2 oz copper

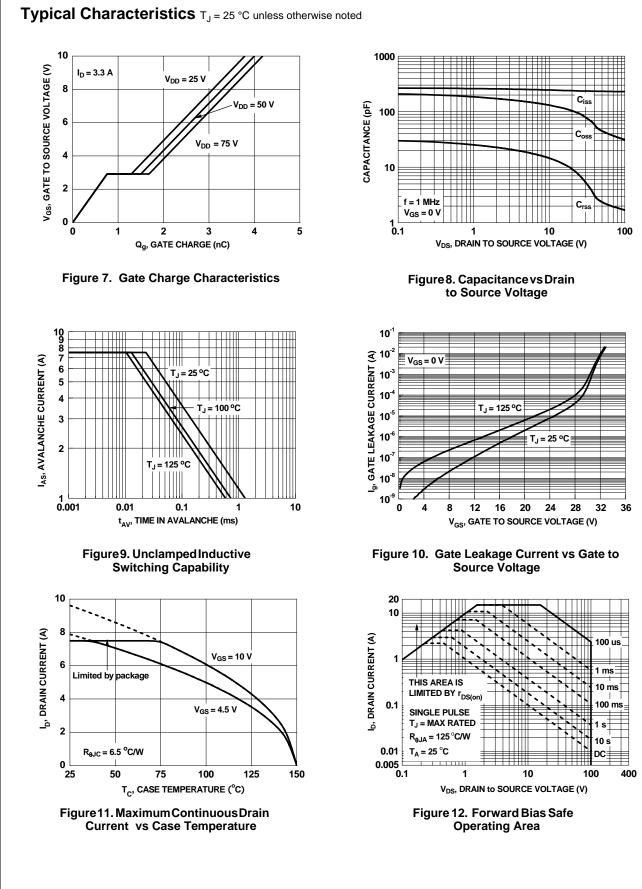
4. The diode connected between gate and source serves only as protection against ESD. No gate overvoltage rating is implied.



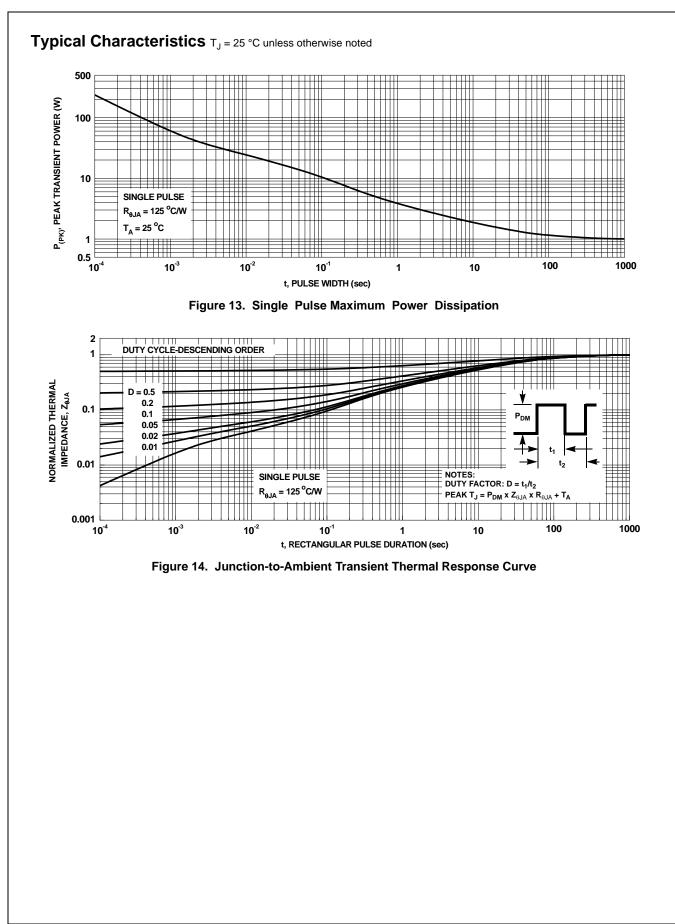
b. 125 °C/W when mounted on a minimum pad of 2 oz copper

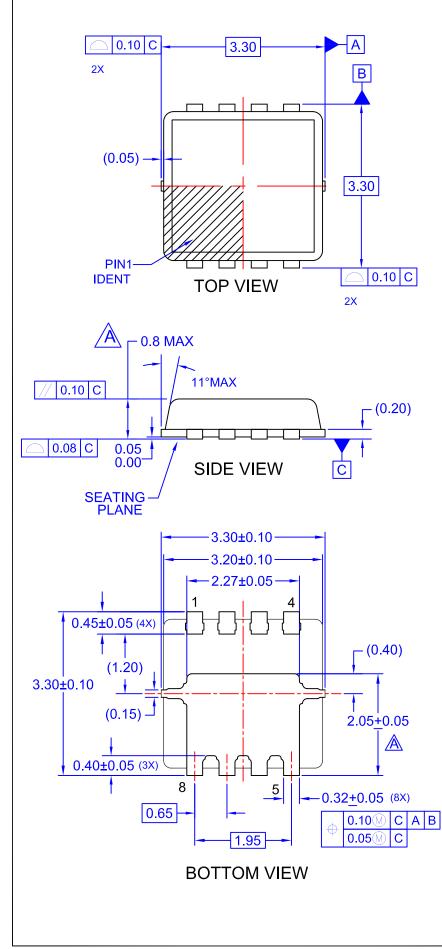
2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%.

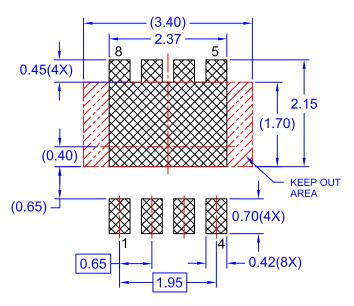




FDMC86116LZ N-Channel Shielded Gate PowerTrench[®] MOSFET







RECOMMENDED LAND PATTERN

NOTES:

- A EXCEPT AS NOTED, PACKAGE CONFORMS TO JEDEC REGISTRATION MO-240 VARIATION BA.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. SEATING PLANE IS DEFINED BY TERMINAL TIPS ONLY
- E. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.
- F. FLANGE DIMENSIONS INCLUDE INTERTERMINAL FLASH OR PROTRUSION. INTERTERMINAL FLASH OR PROTRUSION SHALL NOT EXCEED 0.25MM PER SIDE.
- G. IT IS RECOMMENDED TO HAVE NO TRACES OR VIA WITHIN THE KEEP OUT AREA.
- H. DRAWING FILENAME: MKT-MLP08Trev4.
- I. GENERAL RADII FOR ALL CORNERS SHALL BE 0.20MM MAX.



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